Registration form for Internal users (cAFM)

- Mobile No:
- Guide:
- Number of Samples:
- Processing Mode:
- Nature of samples:

- Sample size:
- Preferred slots:
- Remarks if any:

I hereby read instructions for Registration, Sample Preparation and agree to acknowledge the IRCC Central Facility for Conductive Atomic Force Microscopy (cAFM)@ EE Facility of IIT Bombay in our Publications/Reports/Thesis in which the data is used, with due feedback to cafm@iitb.ac.in